



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Peter J. De Groot. Art Unit : 2877
Serial No. : 10/659,060 Examiner : Marissa Detschel
Filed : September 9, 2003
Title : INTERFEROMETRY METHOD FOR ELLIPSOMETRY, REFLECTOMETRY,
AND SCATTEROMETRY MEASUREMENTS, INCLUDING
CHARACTERIZATION OF THIN FILMS

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

AMENDMENT IN REPLY TO OFFICE ACTION DATED SEPTEMBER 27, 2005

Please amend the above-identified application as follows:

02/03/2006 EFLORES 00000005 10659060

01 FC:1202 100.00 OP

CERTIFICATE OF MAILING BY FIRST CLASS MAIL

I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

January 27, 2006
Date of Deposit

Diane M. Saturno
Signature

Diane M. Saturno
Typed or Printed Name of Person Signing Certificate